Hybrid 8j114 Traveler

April 28, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J114 has die: 036-012 159-095 191-086 191-069 042-037 042-038 042-039 042-040

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j114 classification info. Created 10:36:18 04/26/00

Hybrid 8j114 quality: fair
Chip classification: fair good good good good good good fair
Bad channels (chip-channel): 7-96
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-21-126 0-21-127 0-22-126
   0-25-126 0-25-127 0-26-126 0-28-126 0-28-127 0-30-126 0-30-127 0-32-126
   0-32-127 0-41-125 0-41-126 0-41-127 0-42-126 0-8-125 0-8-126
Channels at pedestal needed for DCMS: 34.6 33.7 34.6 32.6 31.7 32.7 34.7 35.2
```

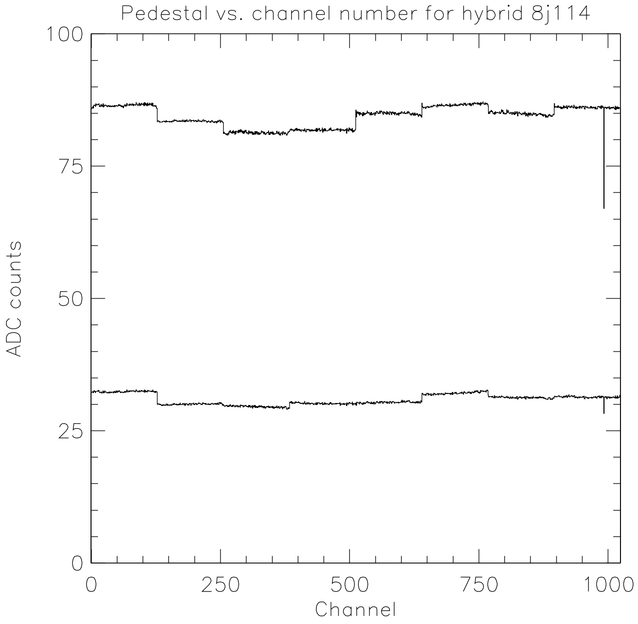
4 Comments

HV tested.

5 Pedestal

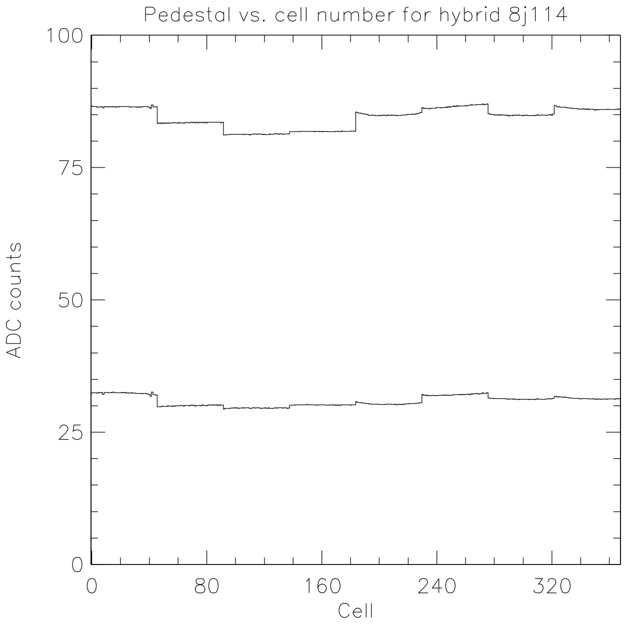
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

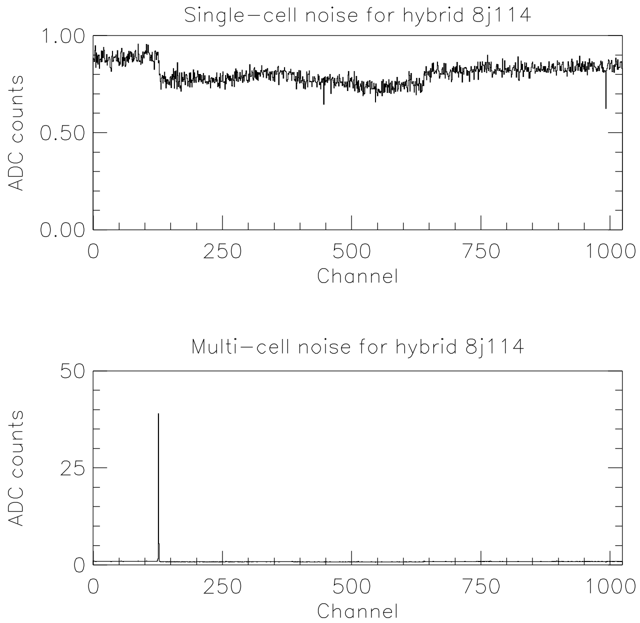
Pedestal vs. Pipeline Cell ID



6 Noise

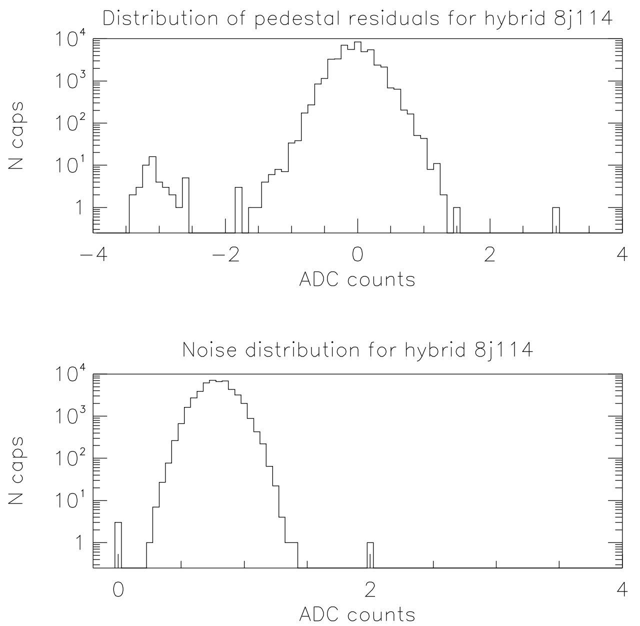
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in